

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. <b>M122-1816</b>	SERIAL NO.
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <b>KUNAL R. PAREKH, ET AL.</b>	
				FILING DATE <b>FILED CONCURRENTLY</b>	GROUP

  

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
yfr	AA	5,338,700	08/94	Dennison et al.			
	AB	5,401,681	03/95	Dennison			
	AC	6,015,983	01/00	Parekh			
	AD	5,981,334	11/99	Chien et al.			
	AE	5,981,333	11/99	Parekh et al.			
	AF	5,923,973	07/99	Chen et al.			
	AG	5,913,129	06/99	Wu et al.			
	AH	5,885,866	03/99	Chen			
	AI	5,874,335	02/99	Jenq et al.			
	AJ	5,763,286	06/98	Figura et al.			
yfr	AK	6,037,220	03/00	Chien et al.			

  

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AL							
AM							
AN							
AO							
AP							

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
yfr	AR		Aoki, Masami, et al., "Fully Self-Aligned 6F <sup>2</sup> Cell Technology For Low Cost 1 Gb DRAM", <i>Symposium</i>
			<i>On VLSI Technology Digest of Technical Papers, IEEE, pp. 22-23 (1996)</i>
	AS		
	AT		

  

EXAMINER <div style="text-align: center; font-size: 1.5em;">yfr</div>	DATE CONSIDERED <div style="text-align: center; font-size: 1.5em;">11/1/02</div>
--	---

  

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

09/955632  
 09/18/01

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. <b>M122-1816</b>	SERIAL NO.		
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT <b>KUNAL R. PAREKH, ET AL.</b>			
				FILING DATE <b>FILED CONCURRENTLY</b>	GROUP		
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,034,391	03/00	Tobita			
	AB	5,897,352	04/99	Lin et al.			
	AC	5,745,336	04/98	Saito et al.			
	AD	5,686,747	11/97	Jost et al.			
	AE	5,383,150	01/95	Nakamura et al.			
	AF	5,786,250	07/98	Wu et al.			
	AG	5,597,756	01/97	Fazan et al.			
	AH	5,639,689	06/97	Woo			
	AI	5,663,085	09/97	Tanigawa			
	AJ	5,418,180	05/95	Brown			
	AK	5,340,765	08/94	Dennison et al.			
	FOREIGN PATENT DOCUMENTS						
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AL						
	AM						
AN							
AO							
AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER		DATE CONSIDERED					
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

APR-10-2002 16:16 FROM

TO 65#1309022\*1816#1703 P.03/36

Form PTU-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1816	SERIAL NO. 09/955,632
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT KUNAL R. PAREKH, ET AL.	
				FILING DATE: September 18, 2001	GROUP 2813

  

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
YR YR YR	AA	6,114,200	09/05/00	Yew et al.			
	AB	6,037,216	03/14/00	Liu et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

  

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AR		
	AS		
	AT		

  

EXAMINER <i>YR</i>	DATE CONSIDERED <i>11/1/02</i>
-----------------------	-----------------------------------

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.